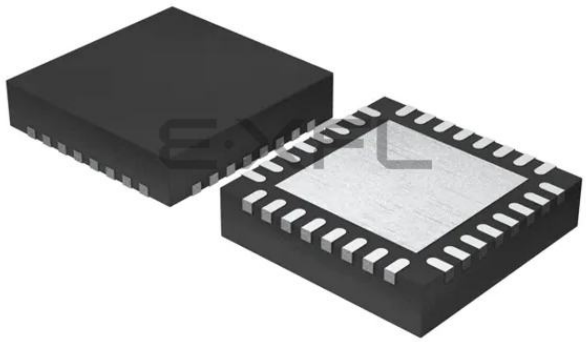

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	50MHz
Connectivity	I²C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	29
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	2.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 20x10/12b SAR; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	32-WFQFN Exposed Pad
Supplier Device Package	32-QFN (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8bb31f16i-b-5qfn32r

Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	Voltage DACs	ADC0 Channels	Comparator 0 Inputs	Comparator 1 Inputs	Pb-free (RoHS Compliant)	Temperature Range	Package
EFM8BB31F64G-B-QSOP24	64	4352	21	4	13	6	7	Yes	-40 to +85 °C	QSOP24
EFM8BB31F32G-B-QFN32	32	2304	29	2[1]	20	10	9	Yes	-40 to +85 °C	QFN32
EFM8BB31F32G-B-QFP32	32	2304	28	2[1]	20	10	9	Yes	-40 to +85 °C	QFP32
EFM8BB31F32G-B-QFN24	32	2304	20	2[1]	12	6	6	Yes	-40 to +85 °C	QFN24
EFM8BB31F32G-B-QSOP24	32	2304	21	2[1]	13	6	7	Yes	-40 to +85 °C	QSOP24
EFM8BB31F16G-B-QFN32	16	2304	29	2[1]	20	10	9	Yes	-40 to +85 °C	QFN32
EFM8BB31F16G-B-QFP32	16	2304	28	2[1]	20	10	9	Yes	-40 to +85 °C	QFP32
EFM8BB31F16G-B-QFN24	16	2304	20	2[1]	12	6	6	Yes	-40 to +85 °C	QFN24
EFM8BB31F16G-B-QSOP24	16	2304	21	2[1]	13	6	7	Yes	-40 to +85 °C	QSOP24
EFM8BB31F64I-B-QFN32	64	4352	29	4	20	10	9	Yes	-40 to +125 °C	QFN32
EFM8BB31F64I-B-QFP32	64	4352	28	4	20	10	9	Yes	-40 to +125 °C	QFP32
EFM8BB31F64I-B-QFN24	64	4352	20	4	12	6	6	Yes	-40 to +125 °C	QFN24
EFM8BB31F64I-B-QSOP24	64	4352	21	4	13	6	7	Yes	-40 to +125 °C	QSOP24
EFM8BB31F32I-B-QFN32	32	2304	29	2[1]	20	10	9	Yes	-40 to +125 °C	QFN32
EFM8BB31F32I-B-QFP32	32	2304	28	2[1]	20	10	9	Yes	-40 to +125 °C	QFP32
EFM8BB31F32I-B-QFN24	32	2304	20	2[1]	12	6	6	Yes	-40 to +125 °C	QFN24
EFM8BB31F32I-B-QSOP24	32	2304	21	2[1]	13	6	7	Yes	-40 to +125 °C	QSOP24
EFM8BB31F16I-B-QFN32	16	2304	29	2[1]	20	10	9	Yes	-40 to +125 °C	QFN32
EFM8BB31F16I-B-QFP32	16	2304	28	2[1]	20	10	9	Yes	-40 to +125 °C	QFP32
EFM8BB31F16I-B-QFN24	16	2304	20	2[1]	12	6	6	Yes	-40 to +125 °C	QFN24
EFM8BB31F16I-B-QSOP24	16	2304	21	2[1]	13	6	7	Yes	-40 to +125 °C	QSOP24

Note:

1. DAC0 and DAC1 are enabled on devices with 2 DACs available.

3. System Overview

3.1 Introduction

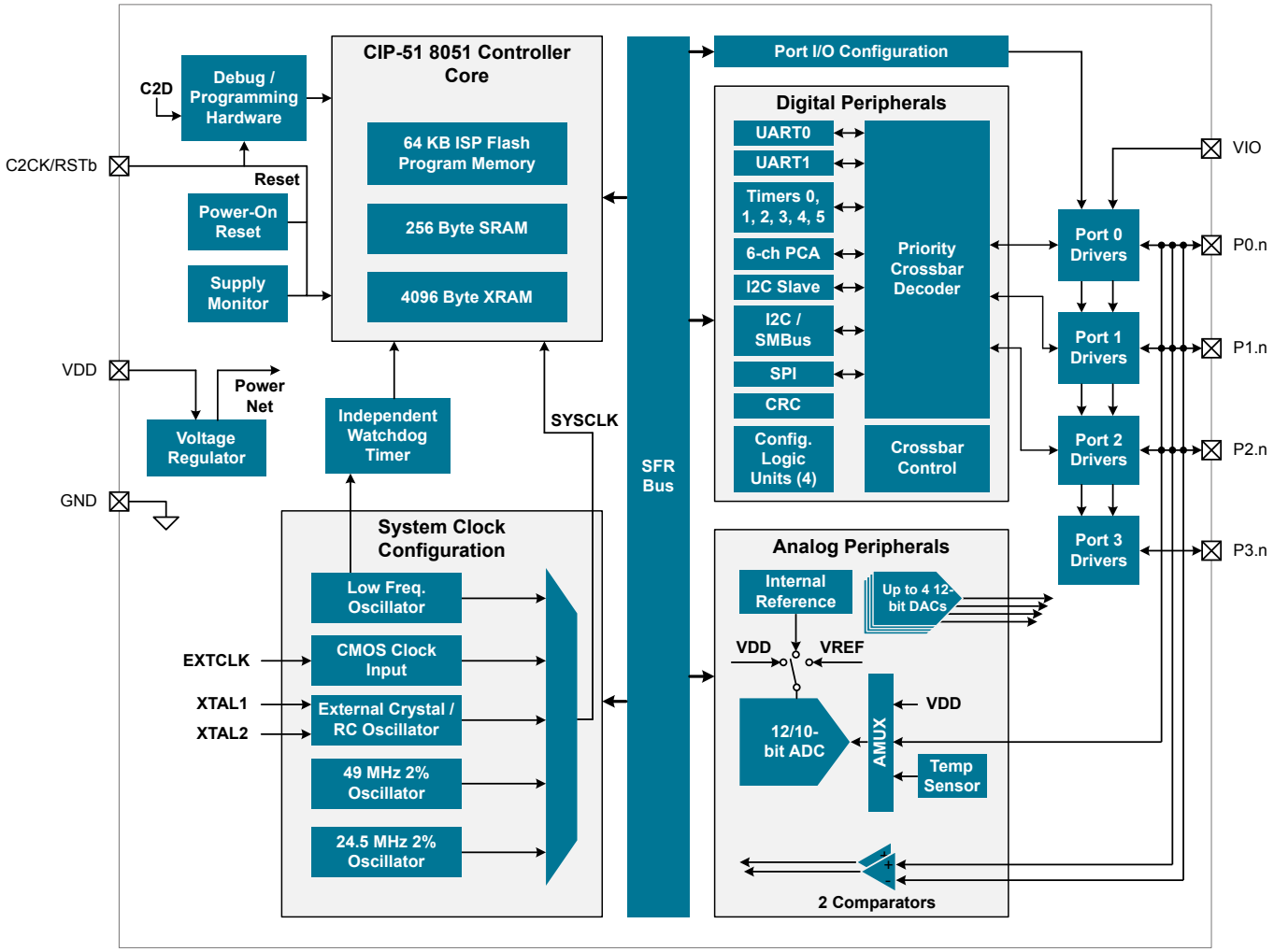

Figure 3.1. Detailed EFM8BB3 Block Diagram

3.2 Power

All internal circuitry draws power from the VDD supply pin. External I/O pins are powered from the VIO supply voltage (or VDD on devices without a separate VIO connection), while most of the internal circuitry is supplied by an on-chip LDO regulator. Control over the device power can be achieved by enabling/disabling individual peripherals as needed. Each analog peripheral can be disabled when not in use and placed in low power mode. Digital peripherals, such as timers and serial buses, have their clocks gated off and draw little power when they are not in use.

Table 3.1. Power Modes

Power Mode	Details	Mode Entry	Wake-Up Sources
Normal	Core and all peripherals clocked and fully operational		
Idle	• Core halted • All peripherals clocked and fully operational • Code resumes execution on wake event	Set IDLE bit in PCON0	Any interrupt
Suspend	• Core and peripheral clocks halted • HFOSC0 and HFOSC1 oscillators stopped • Regulator in normal bias mode for fast wake • Timer 3 and 4 may clock from LFOSC0 • Code resumes execution on wake event	1. Switch SYSCLK to HFOSC0 2. Set SUSPEND bit in PCON1	• Timer 4 Event • SPI0 Activity • I2C0 Slave Activity • Port Match Event • Comparator 0 Falling Edge • CLUn Interrupt-Enabled Event
Stop	• All internal power nets shut down • Pins retain state • Exit on any reset source	1. Clear STOPCF bit in REG0CN 2. Set STOP bit in PCON0	Any reset source
Snooze	• Core and peripheral clocks halted • HFOSC0 and HFOSC1 oscillators stopped • Regulator in low bias current mode for energy savings • Timer 3 and 4 may clock from LFOSC0 • Code resumes execution on wake event	1. Switch SYSCLK to HFOSC0 2. Set SNOOZE bit in PCON1	• Timer 4 Event • SPI0 Activity • I2C0 Slave Activity • Port Match Event • Comparator 0 Falling Edge • CLUn Interrupt-Enabled Event
Shutdown	• All internal power nets shut down • Pins retain state • Exit on pin or power-on reset	1. Set STOPCF bit in REG0CN 2. Set STOP bit in PCON0	• RSTb pin reset • Power-on reset

3.3 I/O

Digital and analog resources are externally available on the device's multi-purpose I/O pins. Port pins P0.0-P2.3 can be defined as general-purpose I/O (GPIO), assigned to one of the internal digital resources through the crossbar or dedicated channels, or assigned to an analog function. Port pins P2.4 to P3.7 can be used as GPIO. Additionally, the C2 Interface Data signal (C2D) is shared with P3.0 or P3.7, depending on the package option.

The port control block offers the following features:

- Up to 29 multi-functions I/O pins, supporting digital and analog functions.
- Flexible priority crossbar decoder for digital peripheral assignment.
- Two drive strength settings for each port.
- State retention feature allows pins to retain configuration through most reset sources.
- Two direct-pin interrupt sources with dedicated interrupt vectors (INT0 and INT1).
- Up to 24 direct-pin interrupt sources with shared interrupt vector (Port Match).

4. Electrical Specifications

4.1 Electrical Characteristics

All electrical parameters in all tables are specified under the conditions listed in Table 4.1 Recommended Operating Conditions on page 14, unless stated otherwise.

4.1.1 Recommended Operating Conditions

Table 4.1. Recommended Operating Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Operating Supply Voltage on VDD	V_{DD}		2.2	—	3.6	V
Operating Supply Voltage on VIO[2, 3]	V_{IO}		2.2	—	V_{DD}	V
System Clock Frequency	f_{SYSCLK}		0	—	50	MHz
Operating Ambient Temperature	T_A	G-grade devices	–40	—	85	°C
		I-grade devices	-40	—	125	°C

Note:

1. All voltages with respect to GND
2. In certain package configurations, the VIO and VDD supplies are bonded to the same pin.
3. GPIO levels are undefined whenever VIO is less than 1 V.

4.1.4 Flash Memory

Table 4.4. Flash Memory

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Write Time[1,2]	t_{WRITE}	One Byte, F_{SYSCLK} = 24.5 MHz	19	20	21	µs
Erase Time[1,2]	t_{ERASE}	One Page, F_{SYSCLK} = 24.5 MHz	5.2	5.35	5.5	ms
V_{DD} Voltage During Programming[3]	V_{PROG}		2.2	—	3.6	V
Endurance (Write/Erase Cycles)	N_{WE}		20k	100k	—	Cycles
CRC Calculation Time	t_{CRC}	One 256-Byte Block SYSCLK = 49 MHz	—	5.5	—	µs

Note:

1. Does not include sequencing time before and after the write/erase operation, which may be multiple SYSCLK cycles.
2. The internal High-Frequency Oscillator 0 has a programmable output frequency, which is factory programmed to 24.5 MHz. If user firmware adjusts the oscillator speed, it must be between 22 and 25 MHz during any flash write or erase operation. It is recommended to write the HFO0CAL register back to its reset value when writing or erasing flash.
3. Flash can be safely programmed at any voltage above the supply monitor threshold (V_{VDDM}).
4. Data Retention Information is published in the Quarterly Quality and Reliability Report.

4.1.5 Power Management Timing

Table 4.5. Power Management Timing

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Idle Mode Wake-up Time	t_{IDLEWK}		2	—	3	SYSCLKs
Suspend Mode Wake-up Time	$t_{SUSPENDWK}$	SYSCLK = HFOSC0 CLKDIV = 0x00	—	170	—	ns
Snooze Mode Wake-up Time	$t_{SLEEPWK}$	SYSCLK = HFOSC0 CLKDIV = 0x00	—	12	—	µs

4.1.9 ADC

Table 4.9. ADC

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N_{bits}	12 Bit Mode		12		Bits
		10 Bit Mode		10		Bits
Throughput Rate (High Speed Mode)	f_S	10 Bit Mode	—	—	1.125	Msps
Throughput Rate (Low Power Mode)	f_S	12 Bit Mode	—	—	340	ksps
		10 Bit Mode	—	—	360	ksps
Tracking Time	t_{TRK}	High Speed Mode	230	—	—	ns
		Low Power Mode	450	—	—	ns
Power-On Time	t_{PWR}		1.2	—	—	µs
SAR Clock Frequency	f_{SAR}	High Speed Mode	—	—	18	MHz
		Low Power Mode	—	—	12.25	MHz
Conversion Time[1]	t_{CNV}	12-Bit Conversion, SAR Clock = 6.125 MHz, System Clock = 49 MHz		2.0		µs
		10-Bit Conversion, SAR Clock = 16.33 MHz, System Clock = 49 MHz		0.658		µs
Sample/Hold Capacitor	C_{SAR}	Gain = 1	—	5.2	—	pF
		Gain = 0.75	—	3.9	—	pF
		Gain = 0.5	—	2.6	—	pF
		Gain = 0.25	—	1.3	—	pF
Input Pin Capacitance	C_{IN}		—	20	—	pF
Input Mux Impedance	R_{MUX}		—	550	—	Ω
Voltage Reference Range	V_{REF}		1	—	V_{IO}	V
Input Voltage Range[2]	V_{IN}		0	—	V_{REF} / Gain	V
Power Supply Rejection Ratio	$PSRR_{ADC}$	At 1 kHz	—	66	—	dB
		At 1 MHz	—	43	—	dB
DC Performance						

4.1.12 DACs

Table 4.12. DACs

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N_{bits}			12		Bits
Throughput Rate	f_S		—	—	200	ksps
Integral Nonlinearity	INL	DAC0 and DAC2 T_A = -40 °C to 125 °C (I-grade parts only)	-11.5	-1.77 / 1.56	11.5	LSB
		DAC0 and DAC3 T_A = -40 °C to 125 °C (I-grade parts only)	-13.5	-2.73 / 1.11	13.5	LSB
Differential Nonlinearity	DNL		-1	—	1	LSB
Output Noise	VREF = 2.4 V f_S = 0.1 Hz to 300 kHz		—	110	—	μV_{RMS}
Slew Rate	SLEW		—	±1	—	V/µs
Output Settling Time to 1% Full-scale	t_{SETTLE}	V_{OUT} change between 25% and 75% Full Scale	—	2.6	5	µs
Power-on Time	t_{PWR}		—	—	10	µs
Voltage Reference Range	V_{REF}		1.15	—	V_{DD}	V
Power Supply Rejection Ratio	PSRR	DC, V_{OUT} = 50% Full Scale	—	78	—	dB
Total Harmonic Distortion	THD	V_{OUT} = 10 kHz sine wave, 10% to 90%	54	—	—	dB
Offset Error	E_{OFF}	VREF = 2.4 V	-8	0	8	LSB
Full-Scale Error	E_{FS}	VREF = 2.4 V	-13	±5	13	LSB
External Load Impedance	R_{LOAD}		2	—	—	kΩ
External Load Capacitance[1]	C_{LOAD}		—	—	100	pF

Note:

1. No minimum external load capacitance is required. However, under low loading conditions, it is possible for the DAC output to glitch during start-up. If smooth start-up is required, the minimum loading capacitance at the pin should be a minimum of 10 pF.

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Negative Hysteresis Mode 3 (CPMD = 11)	HYS_{CP-}	CPHYN = 00	—	-1.5	—	mV
		CPHYN = 01	—	-4	—	mV
		CPHYN = 10	—	-8	—	mV
		CPHYN = 11	—	-16	—	mV
Input Range (CP+ or CP-)	V_{IN}		-0.25	—	V_{IO}+0.25	V
Input Pin Capacitance	C_{CP}		—	7.5	—	pF
Internal Reference DAC Resolution	N_{bits}			6		bits
Common-Mode Rejection Ratio	$CMRR_{CP}$		—	70	—	dB
Power Supply Rejection Ratio	$PSRR_{CP}$		—	72	—	dB
Input Offset Voltage	V_{OFF}	T_A = 25 °C	-10	0	10	mV
Input Offset Tempco	TC_{OFF}		—	3.5	—	µV/°

4.1.14 Configurable Logic

Table 4.14. Configurable Logic

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Propagation Delay	t_{DLY}	Through single CLU Using an external pin	—	—	35.3	ns
		Through single CLU Using an internal connection	—	3	—	ns
Clocking Frequency	F_{CLK}	1 or 2 CLUs Cascaded	—	—	73.5	MHz
		3 or 4 CLUs Cascaded	—	—	36.75	MHz

4.1.16 SMBus

Table 4.16. SMBus Peripheral Timing Performance (Master Mode)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Standard Mode (100 kHz Class)						
I2C Operating Frequency	f_{I2C}		0	—	70[2]	kHz
SMBus Operating Frequency	f_{SMB}		40[1]	—	70[2]	kHz
Bus Free Time Between STOP and START Conditions	t_{BUF}		9.4	—	—	µs
Hold Time After (Repeated) START Condition	$t_{HD:STA}$		4.7	—	—	µs
Repeated START Condition Setup Time	$t_{SU:STA}$		9.4	—	—	µs
STOP Condition Setup Time	$t_{SU:STO}$		9.4	—	—	µs
Data Hold Time	$t_{HD:DAT}$		0	—	—	µs
Data Setup Time	$t_{SU:DAT}$		4.7	—	—	µs
Detect Clock Low Timeout	$t_{TIMEOUT}$		25	—	—	ms
Clock Low Period	t_{LOW}		4.7	—	—	µs
Clock High Period	t_{HIGH}		9.4	—	50[3]	µs
Fast Mode (400 kHz Class)						
I2C Operating Frequency	f_{I2C}		0	—	256[2]	kHz
SMBus Operating Frequency	f_{SMB}		40[1]	—	256[2]	kHz
Bus Free Time Between STOP and START Conditions	t_{BUF}		2.6	—	—	µs
Hold Time After (Repeated) START Condition	$t_{HD:STA}$		1.3	—	—	µs
Repeated START Condition Setup Time	$t_{SU:STA}$		2.6	—	—	µs
STOP Condition Setup Time	$t_{SU:STO}$		2.6	—	—	µs
Data Hold Time	$t_{HD:DAT}$		0	—	—	µs
Data Setup Time	$t_{SU:DAT}$		1.3	—	—	µs
Detect Clock Low Timeout	$t_{TIMEOUT}$		25	—	—	ms
Clock Low Period	t_{LOW}		1.3	—	—	µs
Clock High Period	t_{HIGH}		2.6	—	50[3]	µs

Note:

1. The minimum SMBus frequency is limited by the maximum Clock High Period requirement of the SMBus specification.
2. The maximum I2C and SMBus frequencies are limited by the minimum Clock Low Period requirements of their respective specifications.
3. SMBus has a maximum requirement of 50 µs for Clock High Period. Operating frequencies lower than 40 kHz will be longer than 50 µs. I2C can support periods longer than 50 µs.

Table 4.17. SMBus Peripheral Timing Formulas (Master Mode)

Parameter	Symbol	Clocks
SMBus Operating Frequency	f_{SMB}	f_{CSO} / 3
Bus Free Time Between STOP and START Conditions	t_{BUF}	2 / f_{CSO}
Hold Time After (Repeated) START Condition	$t_{HD:STA}$	1 / f_{CSO}
Repeated START Condition Setup Time	$t_{SU:STA}$	2 / f_{CSO}
STOP Condition Setup Time	$t_{SU:STO}$	2 / f_{CSO}
Clock Low Period	t_{LOW}	1 / f_{CSO}
Clock High Period	t_{HIGH}	2 / f_{CSO}

Note:
1. f_{CSO} is the SMBus peripheral clock source overflow frequency.

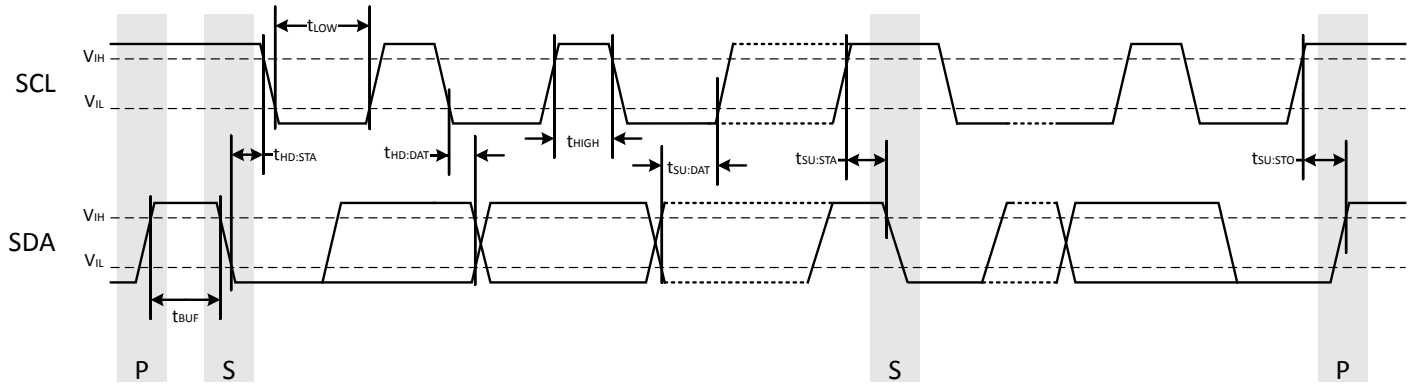

Figure 4.1. SMBus Peripheral Timing Diagram (Master Mode)

4.2 Thermal Conditions

Table 4.18. Thermal Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Thermal Resistance	θ_{JA}	QFN24 Packages	—	30	—	°C/W
		QFN32 Packages	—	26	—	°C/W
		QFP32 Packages	—	80	—	°C/W
		QSOP24 Packages	—	65	—	°C/W

Note:
1. Thermal resistance assumes a multi-layer PCB with any exposed pad soldered to a PCB pad.

5. Typical Connection Diagrams

5.1 Power

Figure 5.1 Power Connection Diagram on page 33 shows a typical connection diagram for the power pins of the device.

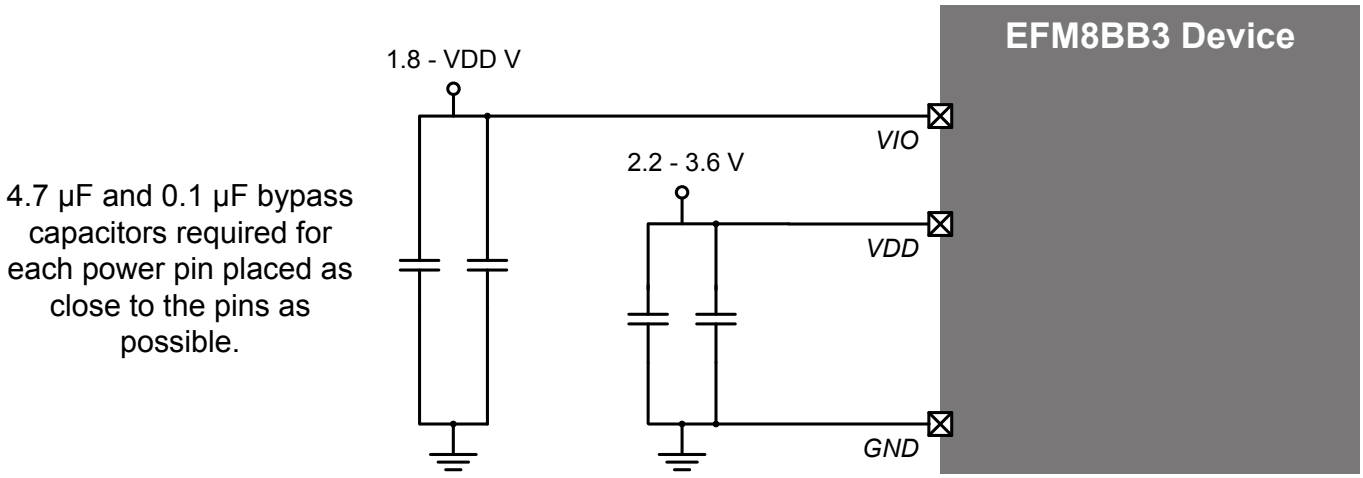

Figure 5.1. Power Connection Diagram

6. Pin Definitions

6.1 EFM8BB3x-QFN32 Pin Definitions

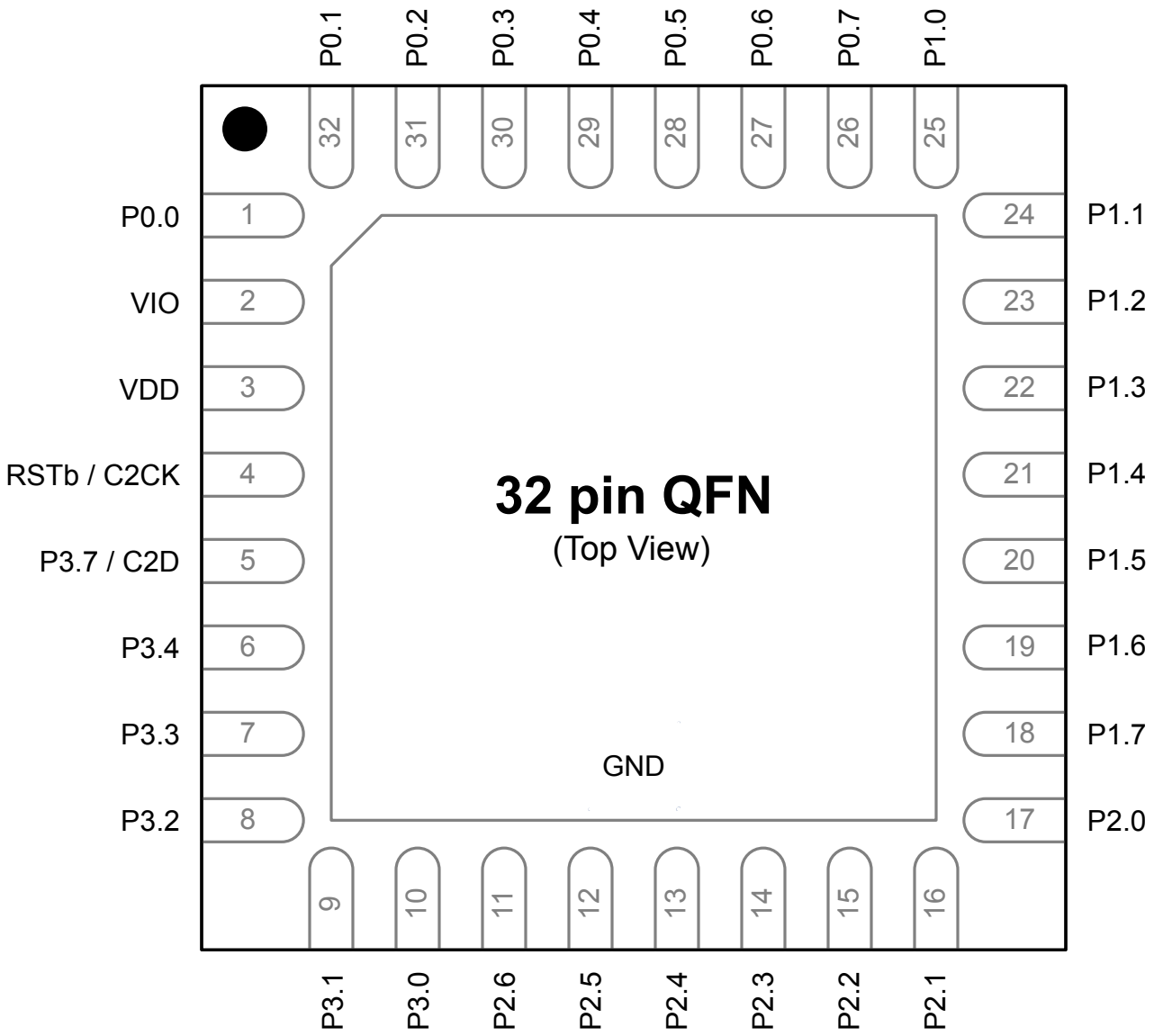

Figure 6.1. EFM8BB3x-QFN32 Pinout

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
12	P1.5	Multifunction I/O	Yes	P1MAT.5 CLU2OUT CLU0B.14 CLU1A.13 CLU2B.13	ADC0.10 CMP1P.4 CMP1N.4
13	P1.4	Multifunction I/O	Yes	P1MAT.4 I2C0_SCL CLU0A.14 CLU1A.12 CLU2B.12	ADC0.9 CMP1P.3 CMP1N.3
14	P1.3	Multifunction I/O	Yes	P1MAT.3 I2C0_SDA CLU0B.13 CLU1B.11 CLU2B.11 CLU3A.13	CMP1P.2 CMP1N.2
15	GND	Ground			
16	P1.2	Multifunction I/O	Yes	P1MAT.2 CLU0A.13 CLU1A.11 CLU2B.10 CLU3A.12	ADC0.8
17	P1.1	Multifunction I/O	Yes	P1MAT.1 CLU0B.12 CLU1B.10 CLU2A.11 CLU3B.13	ADC0.7
18	P1.0	Multifunction I/O	Yes	P1MAT.0 CLU0A.12 CLU1A.10 CLU2A.10 CLU3B.12	ADC0.6

6.4 EFM8BB3x-QSOP24 Pin Definitions

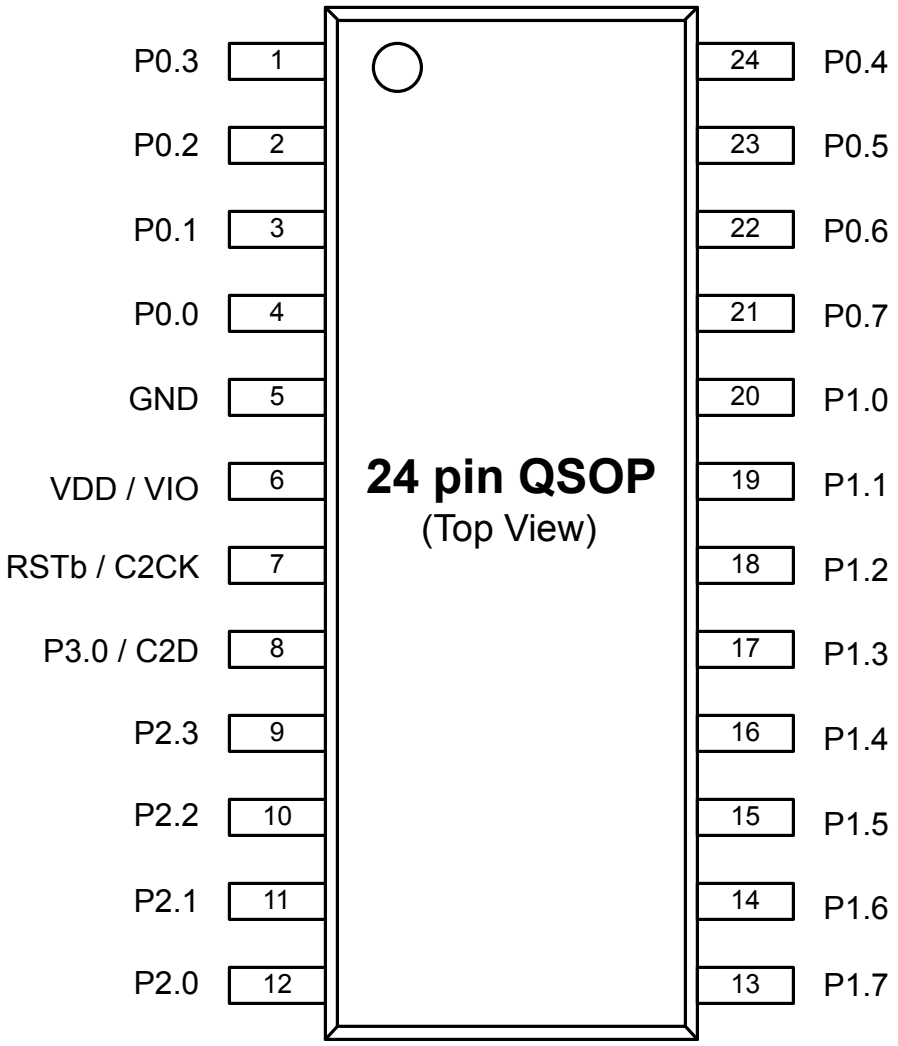

Figure 6.4. EFM8BB3x-QSOP24 Pinout

Table 6.4. Pin Definitions for EFM8BB3x-QSOP24

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3 CLU0B.9 CLU2B.9 CLU3A.9	XTAL2

8. QFP32 Package Specifications

8.1 QFP32 Package Dimensions

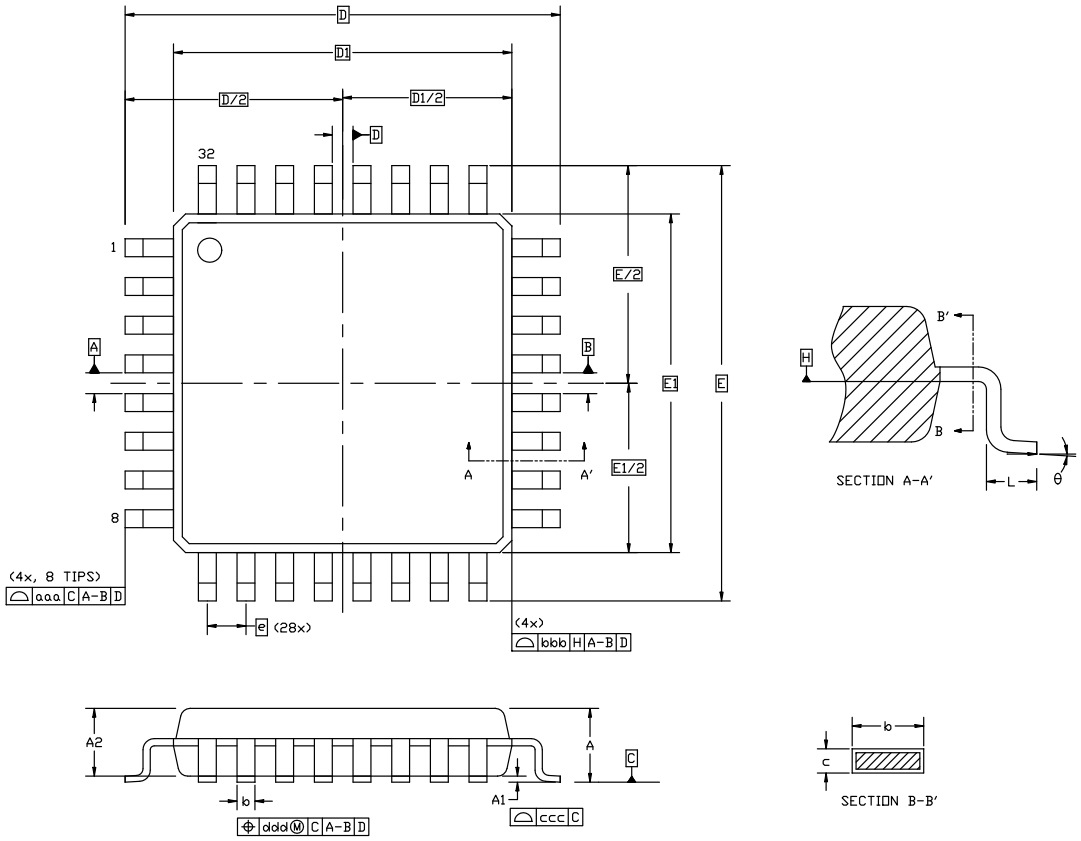

Figure 8.1. QFP32 Package Drawing

Table 8.1. QFP32 Package Dimensions

Dimension	Min	Typ	Max
A	—	—	1.20
A1	0.05	—	0.15
A2	0.95	1.00	1.05
b	0.30	0.37	0.45
c	0.09	—	0.20
D	9.00 BSC		
D1	7.00 BSC		
e	0.80 BSC		
E	9.00 BSC		
E1	7.00 BSC		
L	0.50	0.60	0.70

Dimension	Min	Typ	Max
aaa		0.20	
bbb		0.20	
ccc		0.10	
ddd		0.20	
theta	0°	3.5°	7°

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC outline MS-026.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

8.3 QFP32 Package Marking

Figure 8.3. QFP32 Package Marking

The package marking consists of:

- PPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

9. QFN24 Package Specifications

9.1 QFN24 Package Dimensions

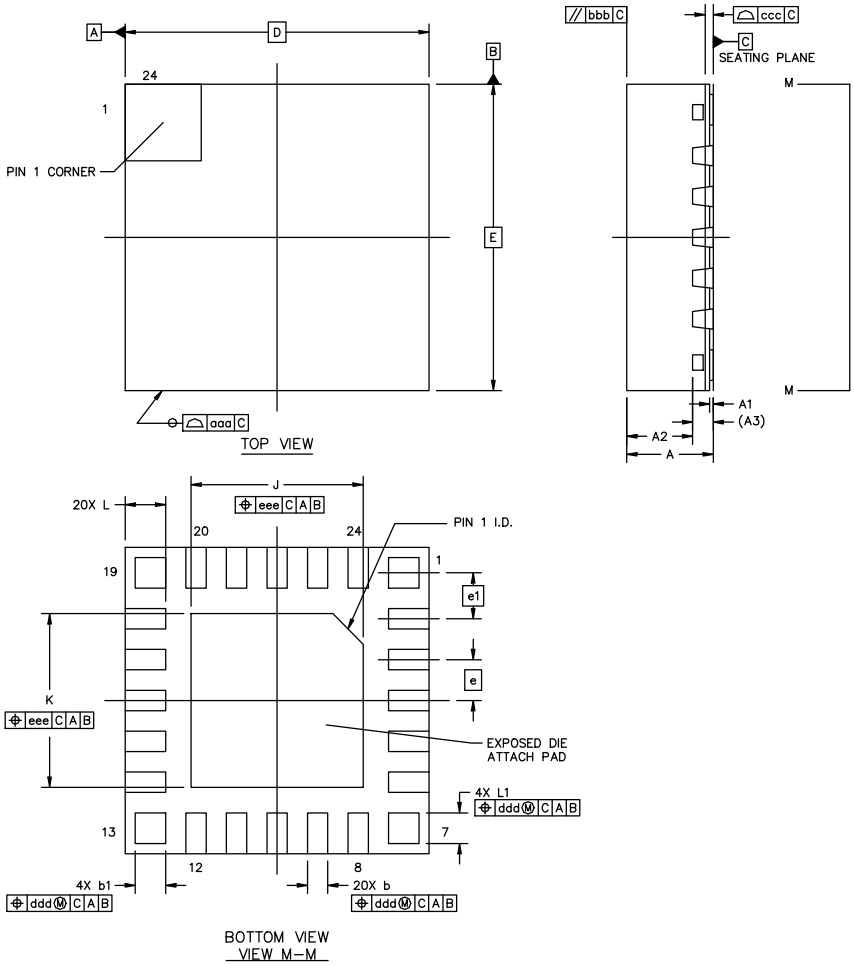

Figure 9.1. QFN24 Package Drawing

Table 9.1. QFN24 Package Dimensions

Dimension	Min	Typ	Max
A	0.8	0.85	0.9
A1	0.00	—	0.05
A2	—	0.65	—
A3		0.203 REF	
b	0.15	0.2	0.25
b1	0.25	0.3	0.35
D		3.00 BSC	
E		3.00 BSC	

Dimension	Min	Typ	Max
e		0.40 BSC	
e1		0.45 BSC	
J	1.60	1.70	1.80
K	1.60	1.70	1.80
L	0.35	0.40	0.45
L1	0.25	0.30	0.35
aaa	—	0.10	—
bbb	—	0.10	—
ccc	—	0.08	—
ddd	—	0.1	—
eee	—	0.1	—

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC Solid State Outline MO-248 but includes custom features which are toleranced per supplier designation.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

11. Revision History

11.1 Revision 1.01

October 21st, 2016

Updated Figure 2.1 EFM8BB3 Part Numbering on page 2 to include the I-grade description.

Updated QFN24 center pad stencil description.

11.2 Revision 1.0

September 6th, 2016

Filled in all TBD values in 4. Electrical Specifications.

Added a note regarding which DACs are available to Table 2.1 Product Selection Guide on page 2.

Added specifications for 4.1.16 SMBus.

Added bootloader pinout information to 3.10 Bootloader.

Added CRC Calculation Time to 4.1.4 Flash Memory.

11.3 Revision 0.4

May 12th, 2016

Filled in TBD values for DAC Integral Nonlinearity in Table 4.12 DACs on page 26.

Added I-grade devices.

Adjusted the Total Current Sunk into Supply Pin and Total Current Sourced out of Ground Pin specifications in 4.3 Absolute Maximum Ratings.

Added Operating Junction Temperature specification to 4.3 Absolute Maximum Ratings.

11.4 Revision 0.3

February 10th, 2016

Added EFM8831F16G-A-QFN24 to Table 2.1 Product Selection Guide on page 2.

Updated Figure 5.2 Debug Connection Diagram on page 34 to move the pull-up resistor on C2D / RSTb to after the series resistor instead of before.

Added mention of the pre-programmed bootloader in 1. Feature List.

Added a reference to *AN945: EFM8 Factory Bootloader User Guide* in 3.10 Bootloader.

Updated all part numbers to revision B.

Adjusted C1, C2, X2, Y2, and Y1 maximums for 7.2 QFN32 PCB Land Pattern.

Adjusted package markings for QFN32 and QSOP24 packages.

Filled in TBD minimum and maximum values for DAC Differential Nonlinearity in Table 4.12 DACs on page 26.

11.5 Revision 0.2

Added information on the bootloader to 3.10 Bootloader.

Updated some characterization TBD values.

11.6 Revision 0.1

Initial release.